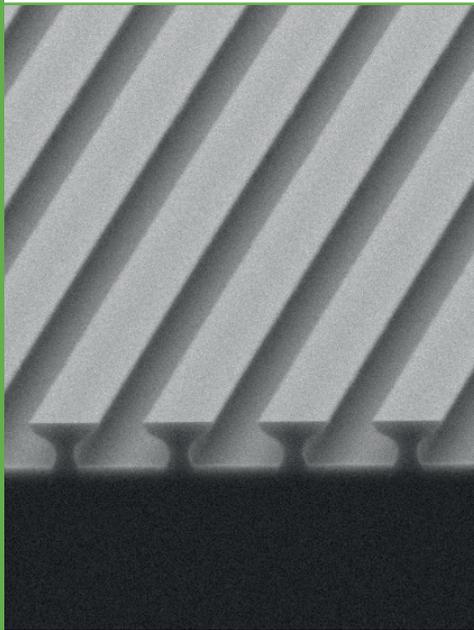




**PFAS-free products -
we pay attention**

*micro resist
technology*

Negative Photoresists for UV, Laser & Electron Beam Lithography



- ma-N 400
- ma-N 1400
- ma-N 2400
- mr-EBL 6000 and mr-UVL 6000
- mr-DWL
- EpoCore and EpoClad

Unique features of the negative photoresists

- Different negative photoresists series designed for various applications:
 - conventional pattern transfer
 - lift-off process
 - use as permanent material
- Ready-to-use solutions in a variety of viscosities

- Made in Germany -



micro resist technology GmbH

Gesellschaft für chemische Materialien spezieller Photoresistsysteme mbH

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12555 Berlin
GERMANY

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fax
mail
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+49 30 64 16 70 100
+49 30 64 16 70 200
sales@microresist.de
www.microresist.com

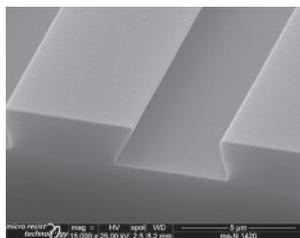
www.microresist.com

For Conventional Pattern Transfer and Single Layer Lift-Off

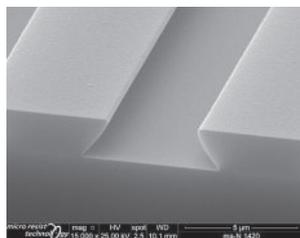
Resist	ma-N 400	ma-N 1400
Spectral sensitivity	300 – 380 nm	300 – 410 nm
Exposure dose @ 365 nm	350 – 1900 mJ/cm ²	300 – 700 mJ/cm ²
Ready-to-use solutions for various film thicknesses @ 3000 rpm	ma-N 402 → 0.2 μm ma-N 405 → 0.5 μm ma-N 415 → 1.5 μm ma-N 420 → 2.0 μm ma-N 440 → 4.1 μm ma-N 490 → 7.5 μm	ma-N 1405 → 0.5 μm ma-N 1407 → 0.7 μm ma-N 1410 → 1.0 μm ma-N 1420 → 2.0 μm ma-N 1440 → 4.0 μm
Thermal stability	up to 110 °C for metal evaporation	up to 160 °C for metal evaporation and sputtering
Developer	ma-D 331/S, ma-D 332/S (NaOH based) ma-D 530/S ma-D 531/S, ma-D 532/S (TMAH based)	ma-D 533/S (TMAH based)

ma-N 1400

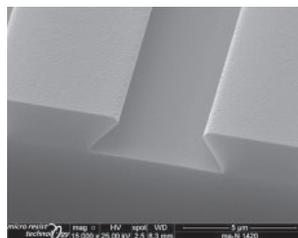
Undercut patterns of 2.2 μm thick ma-N 1420



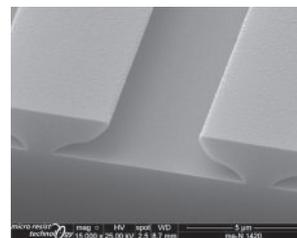
60 s ma-D 533s
→0.5 μm undercut



80 s ma-D 533s
→1.0 μm undercut



100 s ma-D 533s
→1.5 μm undercut



120 s ma-D 533s
→2.2 μm undercut

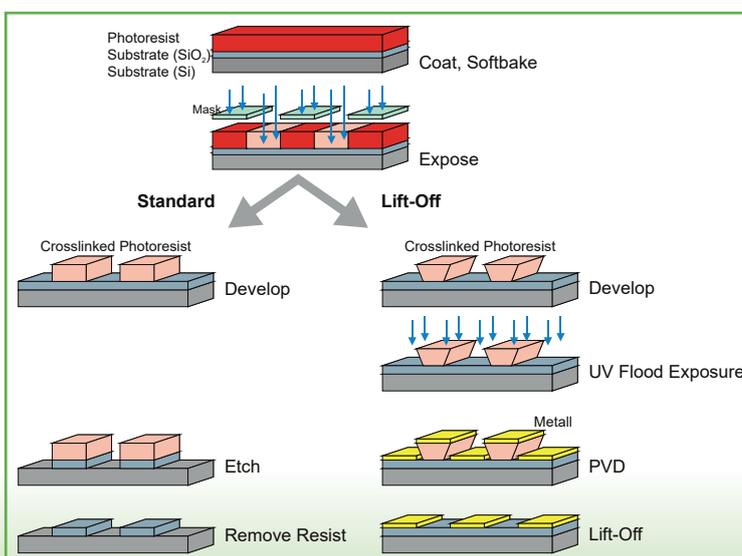
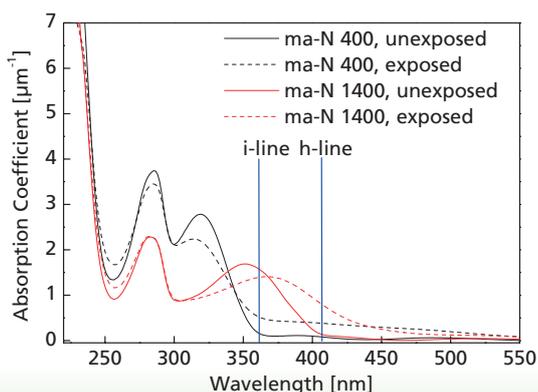
ma-N 400 and ma-N 1400 for conventional pattern transfer, physical vapour deposition (PVD), and lift-off

These two series are mainly used as single layer resist for pattern transfer by PVD and lift-off.

- Tunable pattern profile: vertical to undercut
- Aqueous alkaline development
- Good - excellent thermal pattern stability
- High wet and dry etch resistance
- Easy to remove

Main applications

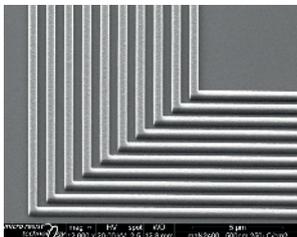
- Microelectronics and micro system technology
- Mask for lift-off processes
- Etch mask for semiconductors and metals



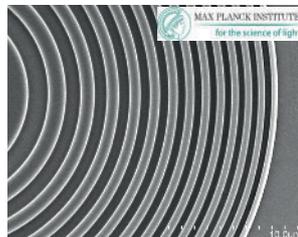
For Thin Film E-Beam, Deep UV or UV Lithography

Resist	ma-N 2400	mr-EBL 6000	mr-UVL 6000
Exposure dose			
E-beam	@ 10 keV 20 – 45 $\mu\text{C}/\text{cm}^2$ @ 20 keV 80 – 200 $\mu\text{C}/\text{cm}^2$ @ 30 keV 95 – 300 $\mu\text{C}/\text{cm}^2$ @ 50 keV 150 – 350 $\mu\text{C}/\text{cm}^2$ @ 100 keV 240 – 550 $\mu\text{C}/\text{cm}^2$	- - 2 – 6 $\mu\text{C}/\text{cm}^2$ 2 – 6 $\mu\text{C}/\text{cm}^2$ 8 – 15 $\mu\text{C}/\text{cm}^2$	- - - - -
Deep UV [248 / 254 / 266 nm] UV [300 – 365 nm]	5 – 20 mJ/cm^2 -	- (400 - 550 mJ/cm^2)	300 - 400 mJ/cm^2
Ready-to-use solutions for various film thicknesses @ 3000 rpm	ma-N 2401 \rightarrow 0.1 μm ma-N 2403 \rightarrow 0.3 μm ma-N 2405 \rightarrow 0.5 μm ma-N 2410 \rightarrow 1.0 μm	mr-EBL 6000.1 \rightarrow 0.1 μm mr-EBL 6000.3 \rightarrow 0.3 μm mr-EBL 6000.5 \rightarrow 0.5 μm	mr-UVL 6000.1 \rightarrow 0.1 μm mr-UVL 6000.3 \rightarrow 0.3 μm mr-UVL 6000.5 \rightarrow 0.5 μm
Developer	ma-D 525 (TMAH based) ma-D 332/ ma-D 331 (NaOH based)	mr-Dev 600 (solvent based)	

ma-N 2400

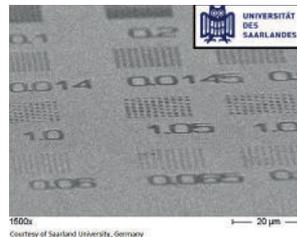


500 nm thick resist elbow pattern

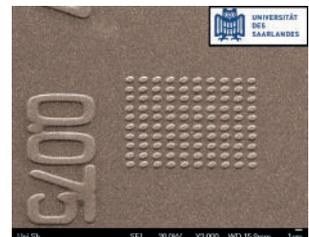


250 nm thick resist Fresnel pattern
(Courtesy of Max Planck Institute for the Science of Light, Germany)

mr-EBL 6000



120 nm thick resist pattern, resolution < 100 nm



98 nm SiC dots 70 nm thick, after ICP RIE SF_6 etching (150 W RF, 200 W) & resist removal

(Pictures - Courtesy of Saarland University, Germany)

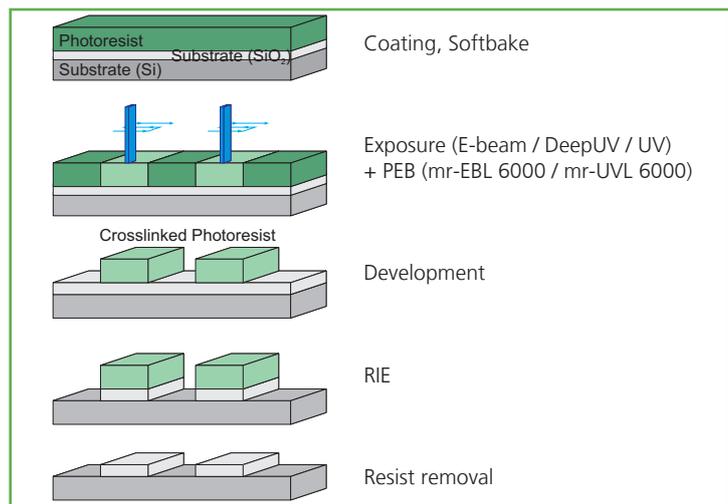
ma-N 2400, mr-EBL 6000, and mr-UVL 6000 for pattern transfer

ma-N 2400 e-beam & Deep UV sensitive

- High resolution capability
- Aqueous alkaline development
- Good thermal stability of the resist patterns
- High wet and dry etch resistance
- Lift-off
- Easy to remove

mr-EBL 6000 high e-beam sensitivity

- Excellent thermal stability of the resist patterns
- High dry and wet etch resistance
- High resolution capability
- Post exposure bake (PEB)



mr-UVL 6000 thin layer UV lithography

- High dry and wet etch resistance
- Excellent thermal stability of the resist patterns
- Post exposure bake (PEB)

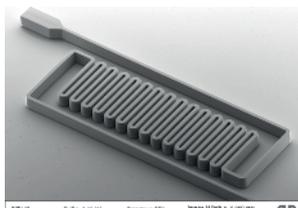
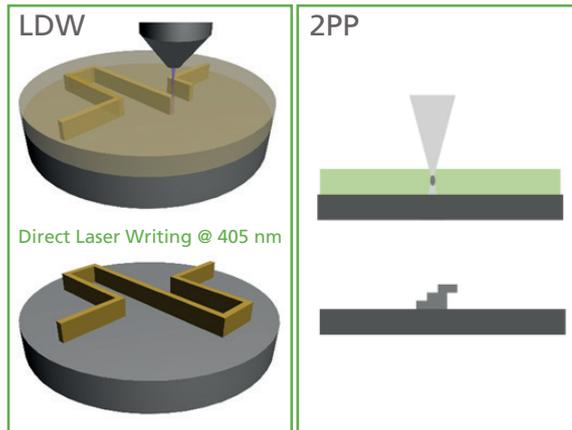
Main applications

- Use in micro- and nanoelectronics
- Manufacturing of semiconductor devices
- Mask for etching, e.g. Si, SiO₂, Si₃N₄ or metals
- Generation of sub 100 nm pattern
- Generation of stamps with nanopatterns

Highly transparent Materials for Low Optical Loss and Standard Applications

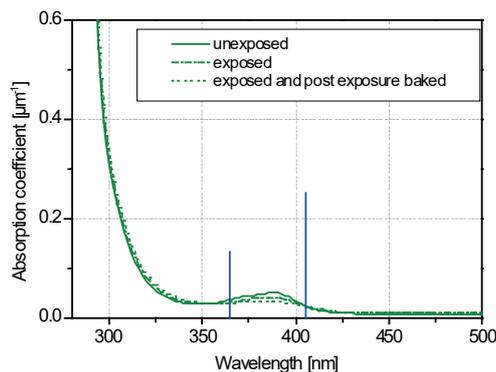
mr-DWL @ 405 nm for Direct Laser Writing (DLW) @ 405 nm & Two Photon Polymerization (2PP)

Resist	mr-DWL
Spectral sensitivity	High sensitivity > 400 nm DLW @ 405 nm
Ready-to-use solutions for various film thicknesses	mr-DWL 5: 3 µm → 12 µm mr-DWL 40: 20 µm → 100 µm mr-DWL 100: 20 µm → 150 µm
Developer	mr-Dev 600 (solvent based)



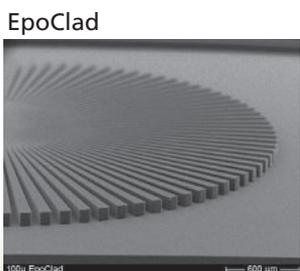
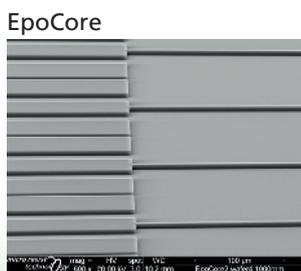
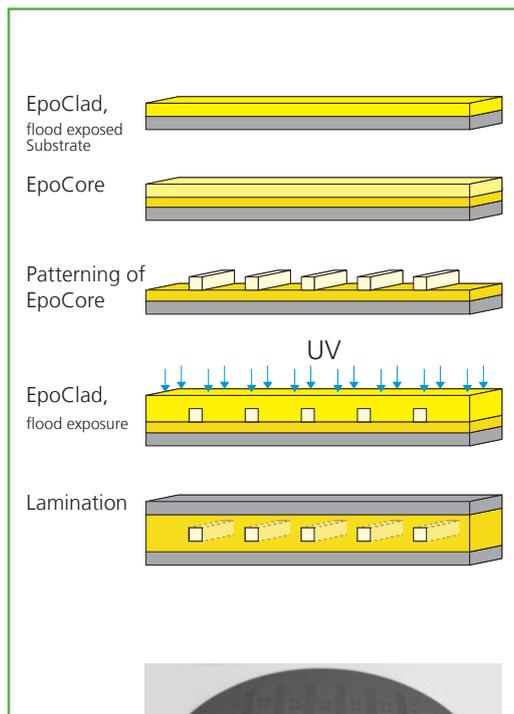
DLW 80 µm 70 µm thick, 2PP
(pictures - DLW: Courtesy of Heidelberg Instruments, 2PP: Fraunhofer IPT Aachen, Germany)

- Main applications**
- Fast and contactless prototyping by DLW & 2PP
 - Optical applications in micro systems technology
 - Etch mask for wet and dry etch processes
 - Mould for electroplating
 - Mould for stamp fabrication/ template manufacture



EpoCore / EpoClad for preparation of polymer waveguides

Resist	EpoCore	EpoClad
Spectral sensitivity	Broadband, 365 nm	
Ready-to-use solutions for various film thicknesses from 1.5 µm to 120 µm	EpoCore 2 EpoCore 5 EpoCore 10 EpoCore 20 EpoCore 50	EpoClad 2 EpoClad 5 EpoClad 10 EpoClad 20 EpoClad 50
Developer	mr-Dev 600 (solvent based)	
Properties of cured resist		
Shrinkage	< 3 %	
Thermal stability	up to 230 °C	
Refractive index @ 830 nm	1.58	1.57
Optical loss	~ 0.2 dB/cm @ 850 nm	
Glass transition temperature	> 180 °C	
Excellent stability after lamination	T > 185°C, pressure 23 kp/cm ² and reflow tests 3 x 15 s @ 230 C°, TCT: 240 x -40 °C to 120 °C	



- Main applications**
- Singlemode (SM) and Multimode (MM) polymeric optical waveguides

